

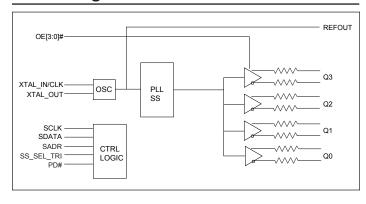


3.3V Very-Low Power 4-Output PCIe Clock Generator With On-chip Termination

Description

The DIODES PI6CG33402C is a four-output very-low power PCIe Gen1/Gen2/Gen3/Gen4/Gen5/Gen6 clock generator. It uses 25MHz crystal or CMOS reference as an input to generate the 100MHz low-power differential HCSL outputs with on-chip terminations. The on-chip termination can save 16 external resistors and make layout easier. An additional buffered reference output is provided to serve as a low-noise reference for other circuitry. It uses Diodes' proprietary PLL design to achieve very-low jitter that meets PCIe Gen1/Gen2/Gen3/Gen4/Gen5/Gen6 requirements. It also provides various options such as different slew rate and amplitude through SMBUS, so users can configure the device easily to get the optimized performance for their individual boards. The device also supports selectable spread-spectrum options to reduce EMI for various applications.

Block Diagram



Features

- 3.3V Supply Voltage
- Crystal/CMOS Input: 25MHz
- Four Differential Low-Power HCSL Outputs with On-chip
- Termination
 Default $Z_{OUT} = 85\Omega$
- Individual Output Enable
- Reference CMOS Output
- Programmable Slew Rate and Output Amplitude for each Output
- Differential Outputs Blocked until PLL is Locked
- Selectable 0%, -0.25%, or -0.5% Spread on Differential Outputs
- Strapping pins or SMBus for Configuration
- Differential Output-to-Output Skew <50ps
- Very-Low Jitter Outputs
 - Differential Cycle-to-Cycle Jitter <50ps
 - PCIe Gen1/Gen2/Gen3/Gen4/Gen5/Gen6 Compliant
 - CMOS REFOUT Phase Jitter
 - <0.3ps RMS, SSC off
 - <1.5ps RMS, SSC on</p>
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- For automotive applications requiring specific change control (i.e. parts qualified to AEC-Q100/101/104/200, PPAP capable, and manufactured in IATF 16949 certified facilities), please contact us or your local Diodes representative.

https://www.diodes.com/quality/product-definitions/

- Packaging (Pb-free & Green):
 - □ 32-lead 5mm × 5mm TQFN

Notes:

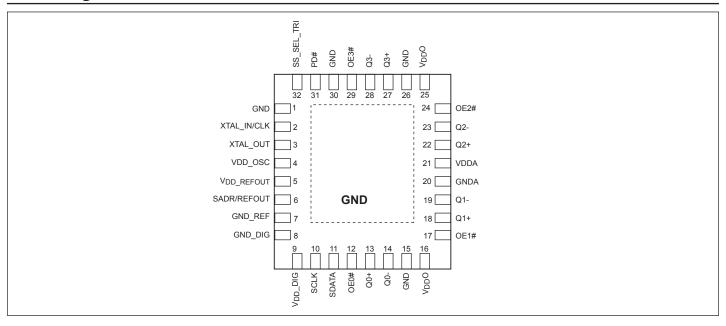
Downloaded from Arrow.com.

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant.
- 2. See https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.





Pin Configuration



Pin Description

Pin #	Pin Name	Ту	pe	Description
1, 15, 26, 30	GND	Power		Ground pin
2	XTAL_IN/CLK	Input		Crystal input or CMOS reference input
3	XTAL_OUT	Output		Crystal output
4	V _{DD} _OSC	Power		Power supply for oscillator circuitry, nominal 3.3V
5	V _{DD} _REFOUT	Power		Power supply for buffered CMOS output
6	SADR/REFOUT	Input/ Output	CMOS	Latch to select SMBus Address or LVCMOS REFOUT. This pin has an internal pulldown
7	GND_REF	Power		Ground for REFOUT
8	GND_DIG	Power		Ground for digital circuitry
9	V _{DD} _DIG	Power		Power supply for digital circuitry, nominal 3.3V
10	SCLK	Input	CMOS	SMBUS clock input, 3.3V tolerant
11	SDATA	Input/ Output	CMOS	SMBUS Data line, 3.3V tolerant
12	OE0#	Input	CMOS	Active low input for enabling Q0 pair. This pin has an internal pulldown. 1 = disable outputs, 0 = enable outputs
13	Q0+	Output	HCSL	Differential true clock output
14	Q0-	Output	HCSL	Differential complementary clock output
16, 25	V_{DDO}	Power		Power supply for differential outputs
17	OE1#	Input	CMOS	Active low input for enabling Q1 pair. This pin has an internal pulldown. 1 = disable outputs, 0 = enable outputs





Pin #	Pin Name	Ту	pe	Description
18	Q1+	Output	HCSL	Differential true clock output
19	Q1-	Output	HCSL	Differential complementary clock output
20	GNDA	Power		Ground for analog circuitry
21	V_{DDA}	Power		Power supply for analog circuitry
22	Q2+	Output	HCSL	Differential true clock output
23	Q2-	Output	HCSL	Differential complementary clock output
24	OE2#	Input	CMOS	Active low input for enabling Q2 pair. This pin has an internal pulldown. 1 = disable outputs, 0 = enable outputs
27	Q3+	Output	HCSL	Differential true clock output
28	Q3-	Output	HCSL	Differential complementary clock output
29	OE3#	Input	CMOS	Active low input for enabling Q3 pair. This pin has an internal pulldown. 1 = disable outputs, 0 = enable outputs
31	PD#	Input	CMOS	Input notifies device to sample latched inputs and start up on first high assertion. Low enters Power Down Mode, and subsequent high assertions exit Power Down Mode. This pin has an internal pullup resistor
32	SS_SEL_TRI	Input	Tri-level	Latched select input to select spread spectrum amount at initial power up. $1 = 0.5\%$ spread, $M = Spread$ off, $0 = Spread$ off. This pin has both internal pull-up and pull-down resistor. Refer to SMBUS byte_1 bit 4, $3 = '01'$ to get -0.25% spread.
Epad	GND	Power		Connect to ground





Table 1. SMBus Address Selection

	SADR	Address	+Read/Write Bit
CLA CCADD CALL CONDU	0	1101000	X
State of SADR on first application of PD#	1	1101010	X

Table 2. Power Management⁽³⁾

PD#	SMBus OE bit	OEn#	Qn+	Qn-	REFOUT
0	X	X	Low ⁽¹⁾	Low ⁽¹⁾	HiZ ⁽²⁾
1	1	0	Running	Running	Running
1	1	1	Disabled ⁽¹⁾	Disabled ⁽¹⁾	Running
1	0	X	Disabled ⁽¹⁾	Disabled ⁽¹⁾	Disabled ⁽⁴⁾

Note:

- 1. The output state is set by B11[1:0] (Low/Low default).
- 2. REF is Hi-Z until the 1st assertion of PD# high. After this, when PD# is low, REF is disabled. If Byte3, bit 5 = 1, REF is running.
- 3. Input High/Low defined at default values for device.
- 4. See SMBUs Byte 3, bit 4.





Maximum Ratings

(Above which useful life may be impaired. For user guidelines, not tested.)

<u> </u>
Storage Temperature65°C to +150°C
Supply Voltage to Ground Potential, V_{DDxx} 0.5V to +4.6V
Input Voltage $-0.5V$ to $V_{\mbox{\scriptsize DD}} + 0.5V$, not exceed 4.6V
SMBus, Input High Voltage
ESD Protection (HBM)
Max Junction Temperature+125°C

Note: Stresses greater than those listed under MAXI-MUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

Operating Conditions

Temperature = T_A ; Supply voltages per normal operation conditions; See test circuits for the load conditions.

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V _{DDO} , V _{DDA} , V _{DD} OSC, V _{DD} DIG, V _{DD} RE- FOUT	Power Supply Voltage		3.135	3.3	3.465	V
I _{DDA}	Analog Power Supply Current	All outputs active @ 100MHz		22	25	mA
I_{DD}	Power Supply Current	All V_{DD} , except V_{DDA} and V_{DDO} , All outputs active @ 100MHz		13	16	mA
I_{DDO}	IO Power Supply Current ⁽³⁾	V _{DDO} , All outputs active @ 100MHz		20	25	mA
I _{DDA_WL}	Analog Power Supply Wake-on-LAN ⁽¹⁾ Current	Q outputs off, REF output running		0.5	1	mA
I _{DD_WL}	Power Supply Wake-on-LAN ⁽¹⁾ Current	All V_{DD} , except V_{DDA} and V_{DDO} , Q outputs off, REF output running		3	6	mA
I _{DDO_WL}	Power Supply Wake-on-LAN ⁽¹⁾ Current for Outputs	Q outputs off, REF output running		1	2	mA
I _{DDA_PD}	Analog Power Supply Power Down ⁽²⁾ Current	All outputs off		0.5	1	mA
I _{DDO_PD}	IO Power Down ⁽²⁾ Current	All outputs off		1	2	mA
I _{DD_PD}	Power Supply Power Down ⁽²⁾ Current	All outputs off		1	2	mA
T_{A}	Ambient Temperature	Industrial grade	-40		85	°C

Note

- 1. Wake-on-LAN mode: PD# = '0' Byte 3, bit 5 = '1'.
- 2. Power down mode: PD# = '0' Byte 3, bit 5 = '0'.
- 3. Output drive 5 inch trace.





Input Electrical Characteristics

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
R _{pu}	Internal pull up resistance			120		ΚΩ
R _{dn}	Internal pull down resistance			120		ΚΩ
C_{XTAL}	Internal capacitance on X_IN and X_OUT pins			8		pF
L _{PIN}	Pin inductance				7	nН

Crystal Characteristic

Parameters	Description	Min.	Тур	Max.	Units
OSCmode	Mode of Oscillation	Fundamental			
FREQ	Frequency		25		MHz
ESR ⁽¹⁾	Equivalent Series Resistance			50	Ω
Cload	Load Capacitance		8		pF
Cshunt	Shunt Capacitance				pF
_	Drive Level			200	μW

Note:

SMBus Electrical Characteristics

Temperature = T_A; Supply voltages per normal operation conditions; See test circuits for the load conditions.

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V _{DDSMB}	Nominal Bus Voltage		2.7		3.6	V
		SMBus, $V_{DDSMB} = 3.3V$	2.1		3.6	
V _{IHSMB}	SMBus Input High Voltage	SMBus, V _{DDSMB} < 3.3V	0.65 V _{DDSMB}			V
37	CMD Int I V-1t	SMBus, $V_{DDSMB} = 3.3V$			0.8	V
V _{ILSMB}	SMBus Input Low Voltage	SMBus, V _{DDSMB} < 3.3V			0.8	v
I _{SMBSINK}	SMBus Sink Current	SMBus at V _{OLSMB}	4			mA
V _{OLSMB}	SMBus Output Low Voltage	SMBus at I _{SMBSINK}			0.4	V
f _{MAXSMB}	SMBus Operating Frequency	Maximum frequency			500	kHz
t _{RMSB}	SMBus Rise Time	(Max V_{IL} - 0.15) to (Min V_{IH} + 0.15)			1000	ns
t _{FMSB}	SMBus Fall Time	(Min V_{IH} + 0.15) to (Max V_{IL} - 0.15)			300	ns

^{1.} ESR value is dependent upon frequency of oscillation





Spread Spectrum Characteristic

Temperature = T_A; Supply voltages per normal operation conditions; See test circuits for the load conditions.

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
f_{MOD}	SS Modulation Frequency	Triangular modulation	30	31.8	33	kHz

LVCMOS DC Electrical Characteristics

Temperature = T_A; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V _{IH}	Input High Voltage	Single-ended inputs, except SMBus	0.75 V _{DD}		V _{DD} +0.3	V
V _{IM}	Input Mid Voltage	SS_SEL_TRI	$0.4 V_{ m DD}$	0.5V _{DD}	$0.6 V_{ m DD}$	V
V _{IL}	Input Low Voltage	Single-ended inputs, except SMBus	-0.3		0.25 V _{DD}	V
I_{IH}	Input High Current	Single-ended inputs, $V_{IN} = V_{DD}$			5	μΑ
I_{IL}	Input Low Current	Single-ended inputs, $V_{IN} = 0V$	-5			μΑ
I_{IH}	Input High Current	Single-ended inputs with pullup/ pulldown resistor, $V_{\rm IN} = V_{\rm DD}$			50	μΑ
I_{IL}	Input Low Current	Single-ended inputs with pullup/ pulldown resistor, $V_{\rm IN} = 0 V$	-50			μΑ
V _{OH}	Output High Voltage	REFOUT, except SMBus; I _{OH} = -2mA	$0.8 \times V_{\mathrm{DD}_{-}}$ refout			V
V _{OL}	Output Low Voltage	REFOUT, except SMBus; $I_{OL} = 2mA$			$\begin{array}{c} 0.2 \times \\ V_{DD_} \\ \text{REFOUT} \end{array}$	V
R _{OUT}	CMOS Output Impedance			20		Ω
C _{IN}	Input Capacitance		1.5		5	pF

LVCMOS AC Characteristics

Temperature = T_A ; Supply voltages per normal operation conditions; See test circuits for the load conditions.

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
f_{INPUT}	Input Frequency	XTAL_IN/CLK		25		MHz
t_{RIN}	Input Rise Time	Single-ended inputs			5	ns
$t_{\rm FIN}$	Input fall time	Single-ended inputs			5	ns
t _{STAB}	Clock Stabilization	From power up and after input clock stabilization or deassertion of PD# to first clock		0.75	1	ms





Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
t _{OELAT}	Output Enable Latency	Q start after OE# assertion Q stop after OE# deassertion	1		3	clocks
t _{PDLAT}	PD# Deassertion	Differential outputs enable after PD# deassertion		20	300	μs
t _{PERIOD}	REFOUT Clock Period	REFOUT, assume input is at 25MHz		40		ns
f _{ACC}	REFOUT Frequency Accuracy ⁽¹⁾	REFOUT, long term accuracy to input		0		ppm
		Byte 3 = 1F, 20% to 80% of V _D . DREF	0.9	1.4	2	V/ns
	DEPOYMENT D. (1)	Byte 3 = 5F, 20% to 80% of V _D . DREF	1.5	2.4	3.2	V/ns
t _{SLEW}	REFOUT Slew Rate ⁽¹⁾	Byte 3 = 9F, 20% to 80% of V _D . DREF	2.0	3.0	3.8	V/ns
		Byte 3 = DF, 20% to 80% of V_{D-} DREF	2.3	3.2	4	V/ns
t_{DC}	REFOUT Duty Cycle ⁽¹⁾	$V_T = V_{DD}/2V$, driven by a Xtal	45	50	55	%
t _{DCDIS}	REFOUT Duty Cycle Distortion	$V_T = V_{DD}/2V$, driven by an external source	-2	0	+2	%
tJITCC	REFOUT Cycle-Cycle Jitter	$V_T = V_{DD}/2V$, driven by a Xtal		70	150	ps
	DEFOUTE DI LITTE DAG	12kHz to 5MHz, SSC off, driven by a Xtal		0.16	0.3	ps
t _{JIТРН}	REFOUT Phase Jitter, RMS	12kHz to 5MHz, SSC on, driven by a Xtal		0.9	1.5	ps
		1kHz offset, driven by a Xtal		-149	-135	dBc/Hz
tJITN	Noise Floor	10kHz offset to Nyquist, driven by a Xtal		-158	-140	dBc/Hz

Note:

HCSL Output Characteristics

Temperature = T_A; Supply voltages per normal operation conditions; See test circuits for the load conditions.

Symbol	Parameters	Condition	Min.	Тур.	Max.	Units
V _{OH}	Output Voltage High ⁽¹⁾	Statistical measurement on	660	784	850	mV
V _{OL}	Output Voltage Low ⁽¹⁾	single-ended signal using oscilloscope math function	-150		150	mV
V _{OMAX}	Output Voltage Maximum ⁽¹⁾	Measurement on single-ended		816	1150	mV
V _{OMIN}	Output Voltage Minimum ⁽¹⁾	signal using absolute value	-300	-42		mV
V _{OC}	Output Cross Voltage ^(1,2,4)		250	430	550	mV

 $^{1. \}quad Guaranteed \ by \ design \ and \ characterization-not \ 100\% \ tested \ in \ production.$





Symbol	Parameters	Condition	Min.	Тур.	Max.	Units
DV _{OC}	V _{OC} Magnitude Change ^(1,2,5)			12	140	mV

Note:

- 1. At default SMBUS amplitude settings.
- 2. Guaranteed by design and characterization—not 100% tested in production.
- 3. Measured from differential waveform.
- 4. This one is defined as voltage where Q+ = Q- measured on a component test board and only applied to the differential rising edge.
- 5. he total variation of all Vcross measurements in any particular system. This is a subset of Vcross_min/max allowed.

HCSL Output AC Characteristics

Temperature = T_A; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Condition	Min.	Тур.	Max.	Units
f_{OUT}	Output Frequency			100		MHz
_	Slew Rate ^(1,2,3)	Scope averaging on fast setting	2.5	3.2	4	V/ns
t_{RF}	Siew Rate	Scope averaging on slow setting	2.2	3	3.7	V/ns
Dt _{RF}	Slew Rate Matching ^(1,2,4)	Scope averaging on		7	15	%
t_{DC}	Duty Cycle ^(1,2)	Measured differentially, PLL Mode	45	50	55	%
t _{SKEW}	Output Skew ^(1,2)	Averaging on, V _T = 50%		20	50	ps
tj _{c-c}	Cycle-to-Cycle Jitter ^(1,2)			20	50	ps

Note:

- 1. Guaranteed by design and characterization—not 100% tested in production.
- 2. Measured from differential waveform.
- 3. Slew rate is measured through the Vswing voltage range centered around differential 0V, within ±150mV window.
- 4. It is measured using a ± 75 mV window centered on the average cross point.





PCIe Common Clock (CC) Architecture Jitter

Symbol	Parameters	Condition	Min.	Тур.	Max.	Spec Limit	Units
		PCIe 1.0		20	30	86	ps (pkpk)
		PCIe 2.0 Low Band, 10kHz < f < 1.5MHz (PLL BW 5-16MHz or 8-5MHz, CDR = 10MHz)		0.1	0.2	3	ps
t _{jPHASE}	Integrated phase jitter (RMS)	PCIe 2.0 High Band, 1.5MHz < f < Nyquist (50MHz); (PLL BW 5-16MHz or 8-5MHz, CDR = 10MHz)		0.4	0.5	3.1	ps
		PCIe 3.0 (PLL BW 2-4MHz or 2-5MHz, CDR = 10MHz)		0.15	0.2	1	ps
		PCIe 4.0 (PLL BW 2-4MHz or 2-5MHz, CDR = 10MHz)		0.15	0.2	0.5	ps
		PCIe 5.0		0.05	0.06	0.15	ps
		PCIe 6.0		0.03	0.04	0.1	ps

PCIe Independent Reference Clock Architecture Jitter

Symbol	Parameters	Condition	Min.	Тур.	Max.	Spec Limit	Units
		PCIe 3.0 SRIS (PLL BW 2-4MHz or 2-5MHz, CDR = 10MHz)		0.15	0.25		ps
t _j PHASE	Integrated phase jitter (RMS)	PCIe 4.0 SRIS (PLL BW 2-4MHz or 2-5MHz, CDR = 10MHz)		0.15	0.25		ps
		PCIe 5.0 SRIS		0.04	0.07		ps
		PCIe 6.0 SRIS		0.03	0.05		ps





Differential Output Clock Periods - Spread Spectrum Disabled

			Mea	surement Wir	ndow			
Center	1 clock	1 μs	0.1 s	0.1 s	0.1 s	1 μs	1 clock	
Freq. MHz	-c2c jitter AbsPer Min	-SSC Short- term Avg. Min	-ppm Long- term Avg. min	0 ppm Period Nominal	+ppm Long-term Avg. max	+SSC Short-term Avg. Max	-c2c jitter AbsPer Max	Units
100.00	9.94900		9.99900	10.00000	10.00100		10.05100	ns

Differential Output Clock Periods - Spread Spectrum Enabled

			Mea	surement Wir	ndow			
Center	1 clock	1 μs	0.1 s	0.1 s	0.1 s	1 μs	1 clock	
Freq. MHz	-c2c jitter AbsPer Min	-SSC Short- term Avg. Min	-ppm Long- term Avg. min	0 ppm Period Nominal	+ppm Long-term Avg. max	+SSC Short-term Avg. Max	-c2c jitter AbsPer Max	Units
99.75	9.94906	9.99906	10.02406	10.02506	10.02607	10.05107	10.10107	ns

Note:

- 1. Guaranteed by design and characterization—not 100% tested in production.
- 2. All long term accuracy and clock period specifications are guaranteed assuming REF is trimmed to 25MHz.





SMBus Serial Data Interface

PI6CG33402C is a slave-only device that supports block read and block write protocol using a single 7-bit address and read/write bit as shown below.

Read and write block transfers can be stopped after any complete byte transfer.

Address Assignment

A6	A5	A4	A3	A2	A1	A0	R/W
1	1	0	1	0	SADR	0	1/0

Note: SMBus address is latched on SADR pin

How to Write

1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	8 bits	1 bit	8 bits	1 bit	8 bits	1 bit	1 bit
Start bit	Add.	W(0)	Ack	Beginning Byte loca- tion = N	Ack	Data Byte count = X	Ack	Beginning Data Byte (N)	Ack	 Data Byte (N+X-1)	Ack	Stop bit

How to Read

1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	8 bits	1 bit
Start bit	Address	W(0)	Ack	Beginning Byte location = N	Ack	Repeat Start bit	Address	R(1)	Ack	Data Byte count = X	Ack	Beginning Data Byte (N)	Ack

8 bits	1 bit	1 bit
Data Byte	NI A als	Stop bit
(N+X-1)	NAck	Stop bit

Byte 0	Byte 0: Output Enable Register					
Bit	Control Function	Description	Туре	Power-up Condition	0	1
7	Reserved			0		
6	Reserved			0		
5	Reserved			0		
4	Reserved			0	Can D11[1.0]	
3	Q3_OE	Q3 output enable	RW	1	See B11[1:0]	Pin Control
2	Q2_OE	Q2 output enable	RW	1		Pin Control
1	Q1_OE	Q1 output enable	RW	1		Pin Control
0	Q0_OE	Q0 output enable	RW	1		Pin Control

Note:

1. A low on these bits will override the OE# pins and force the differential outputs to the state indicated by B11[1:0] (Low/Low default).





Byte	1: SS Spread Spectrum	and Control Register				
Bit	Control Function	Description	Туре	Power-up Condition	0	1
7	SSENRB1	SS Enable Readback Bit1	R	Latch	'00' for SS_SEL	_TRI = '0',
6	SSENRB0	SS Enable Readback Bit0	R	Latch	'10' for SS_SEL_TRI = 'M', '11' for SS_SEL_TRI ='1'	
5	SSEN_SWCTR	Enable SW control of SS	RW	0	Values in B1[7:6] control SS amount	Values in B1[4:3] control SS amount
4	SSENSW1	SS enable SW control Bit1	RW ⁽¹⁾	0	'00' = SS off, '01	' = -0.25% SS,
3	SSENSW0	SS enable SW control Bit0	RW ⁽¹⁾	0	'10' = SS off,, '11'	= -0.5% SS
2	Reserved			1		
1	Amplitude1	Control output amplitude	RW	1	'00' = 0.6V, '01' = 0.68V, '10' =	
0	Amplitude0	Control output amplitude	RW	0	0.75V, '11' = 0.85	5V

Note:

^{1.} Spread must be selected OFF or ON with the hardware latch pin. These bits should not be used to turn spread ON or OFF after power up. These bits can be used to change the spread amount, and B1[5] must be set to a 1 for these bits to have any effect on the part. If These bits are used to turn spread OFF or ON, the system will need to be reset.

Byte 2	Byte 2: Differential Output Slew Rate Control Register						
Bit	Control Function	Description	Туре	Power-up Condition	0	1	
7	Reserved			1			
6	Reserved			1			
5	Reserved			1			
4	Reserved			1			
3	SLEWRATECTR_Q3	Control slew rate of Q3	RW	1	Slow setting	Fast setting	
2	SLEWRATECTR_Q2	Control slew rate of Q2	RW	1	Slow setting	Fast setting	
1	SLEWRATECTR_Q1	Control slew rate of Q1	RW	1	Slow setting	Fast setting	
0	SLEWRATECTR_Q0	Control slew rate of Q0	RW	1	Slow setting	Fast setting	





Byte 3	: REF Control Registe	r				
Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	DEEGI EMD ATE	Class with a souther life in DEE	RW	0	'00' = 1.4V/ns '	01' = 2.4V/ns,
6	REFSLEWRATE	Slew rate control for REF	RW	1	'10' = 3V/ns, '11	1' = 3.2V/ns
5	REF_PDSTATE	Wake-on-Lan enable for REF	RW	0	REF = Disabled in PD state ⁽¹⁾	REF = running in PD state
4	REF_OE	Output enable for REF	RW	1	REF = Disabled ⁽¹⁾	REF = running
3	Reserved			1		
2	Reserved			1		
1	Reserved			1		
0	Reserved			1		

Note:

1. The disabled state depends on Byte11[1:0]. '00' = Low, '01' = HiZ, '10' = Low, '11' = High.

Byte 4: Reserved						
Bit	Control Function	Description	Туре	Power Up Condition	0	1
7:0	Reserved			0x40		
_						

Byte 5: Revision and Vendor ID Register

Bit	Control Function	Description	Туре	Power Up Condition	0 1	
7	RID3		R	0		
6	RID2	evision ID	R	0	D 0000	
5	RID1		R	0	Rev = 0000	
4	RID0		R	0		
3	PVID3		R	0		
2	PVID2		R	0	Diodes = 0011	
1	PVID1	endor ID	R	1		
0	PVID0		R	1		





Byte 6	: Device Type/Device	ID Register					
Bit	Control Function	Description	Туре	Power-up Condition	0	1	
7	DTYPE1	5	R	0	'00' = CG, '01'	= ZDB,	
6	DTYPE0	Device type	R	0	'10' = Reserved, '11' = NZDB		
5	DID5		R	0			
4	DID4		R	0			
3	DID3	D : ID	R	0	0001001:	0.411	
2	DID2	Device ID	R	1	000100 binar	у, 04нех	
1	DID1		R	0			
0	DID0		R	0			
Byte 7	: Byte Count Register						
Bit	Control Function	Description	Туре	Power-up Condition	0	1	
7	Reserved			0			
6	Reserved			0			
5	Reserved			0			
4	BC4		RW	0			
3	BC3		RW	1	Writing to th	is register	
2	BC2	Byte count programming	RW	0	configures ho	w many bytes are	
1	BC1		RW	0	read back, de	fault is 8 bytes	
0	BC0		RW	0			
Byte 8	and 9: Reserved						
Bit	Control Function	Description	Туре	Power-up Condition	0	1	
7:0	Reserved			B8: 0x36 B9: 0x00			
Byte 1	0: PD Restore		·				
Bit	Control Function	Description	Туре	Power-up Condition	0	1	
7	Reserved			0			
6	PD Restore	PD Restore to default configuration	RW	1	Clear PD Config	Keep PD Config	
5:0	Reserved			0			





Byte 1	1: Stop Control					
Bit	Control Function	Description	Туре	Power-up Condition	0	1
7:2	Reserved			0		
1	STP1	Total Consolinate DIF Outside Divide Cate	RW	0	00 = Low/Low	10 = High/ Low
0	STP0	True/ Compliment DIF Output Disable Sate	RW	0	01 = HiZ/HiZ	11 = Low/ High
Byte 1	2: Impedance Control					
Bit	Control Function	Description	Туре	Power-up Condition	0	1
7	Q1_Zout1	Q1 Zout	RW			
6	Q1_Zout0	Q1 Zout	RW			
5	Reserved		·	01	00 = Reserved	
4	Reserved				$01 = 85\Omega$	
3	Q0_Zout1	Q0 Zout	RW	01	$10 = 100\Omega$ $11 = Reserved$	
2	Q0_Zout0	Q0 Zout	RW			
1	Reserved					
0	Reserved					
Byte 1	3: Impedance Control					
Bit	Control Function	Description	Туре	Power-up Condition	0	1
7	Reserved					
6	Reserved					
5	Q3_Zout1	Q3 Zout	RW		00 = Reserved	
4	Q3_Zout0	Q3 Zout	RW	01	$01 = 85\Omega$	
3	Q2_Zout1	Q2 Zout	RW		$10 = 100\Omega$	
2	Q2_Zout0	Q2 Zout	RW		11 = Reserved	
1	Reserved					
0	Reserved					





Byte 1	4: OE Termination Co	ntrol				
Bit	Control Function	Description	Type	Power-up Condition	0	1
7	OE1_term1	OE1 Pullup or down	RW	0	00 = None	10 = Pullup
6	OE1_term0	OE1 Pullup or down	RW	1	01 = Pull- down	11 = Pullup and Down
5	Reserved			0		
4	Reserved			1		
3	OE0_term1	OE0 Pullup or down	RW	0	00 = None	10 = Pullup
2	OE0_term0	OE0 Pullup or down	RW	1	01 = Pull- down	11 = Pullup and Down
1	Reserved			0		
0	Reserved			1		
Byte 1	5: OE Termination Co	ntrol				
Bit	Control Function	Description	Type	Power-up Condition	0	1
7	Reserved			0		
6	Reserved			1		
5	OE3_term1	OE3 Pullup or down	RW	0	00 = None	10 = Pullup
4	OE3_term0	OE3 Pullup or down	RW	1	01 = Pull- down	11 = Pullup and Down
3	OE2_term1	OE2 Pullup or down	RW	0	00 = None	10 = Pullup
2	OE2_term0	OE2 Pullup or down	RW	1	01 = Pull- down	11 = Pullup and Down
1	Reserved			0		
0	Reserved			1		
Byte 1	6: Power Good Termin	nation Control				
Bit	Control Function	Description	Туре	Power-up Condition	0	1
7:2	Reserved			0x09		
1	PWRGD_PD1	Clade Description of the Clade Description of	RW	1	00 = None	10 = Pullup
0	PWRGD_PD0	Clock Power Good and Power Down Pullup or Pulldown	RW	0	01 = Pull- down	11 = Pullup and Down
Dyrta 1	7: Reserved				•	





Byte 1	18: Enable Pin Control					
Bit	Control Function	Description	Туре	Power-up Condition	0	1
7	Reserved			0		
6	OE3_Enable	Sets Enable High or Low	RW	0	Enable = Low	Enable = High
5	OE2_Enable	Sets Enable High or Low	RW	0	Enable = Low	Enable = High
4	Reserved			0		
3	OE1_Enable	Sets Enable High or Low	RW	0	Enable = Low	Enable = High
2	Reserved			0		
1	OE0_Enable	Sets Enable High or Low	RW	0	Enable = Low	Enable = High
0	Reserved			0		

Byte 19: Power Down Pin Control

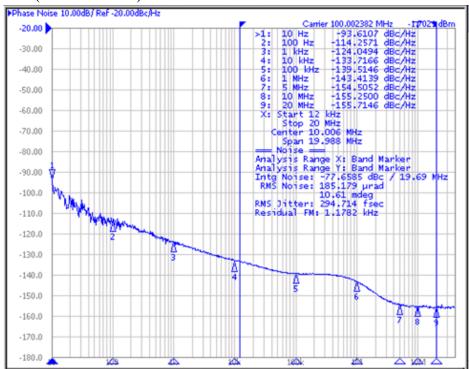
Bit	Control Function	Description	Туре	Power-up Condition	0	1
7:1	Reserved			0		
0	PWRGD_PD	PWRGD_PD Active via Pullup or Pulldown	RW	0	Power Down = Low	Power Down = High



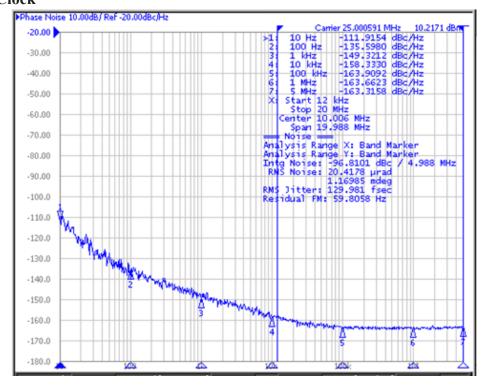


Phase Noise Plots

100MHz HCSL Clock (12k to 20MHz)



25MHz CMOS Clock





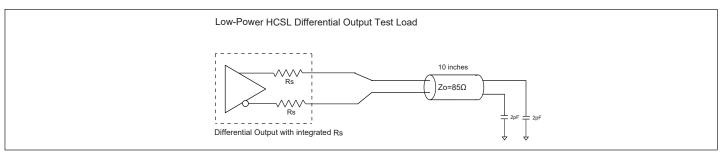


Figure 1. Low-Power HCSL Test Circuit

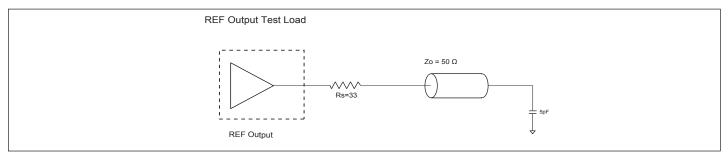


Figure 2. CMOS REF Test Circuit

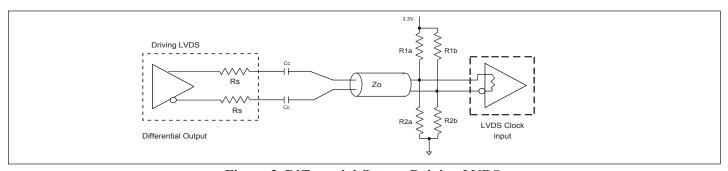


Figure 3. Differential Output Driving LVDS

Table 3. Alternate Differential Output Terminations ($Z_O = 85\Omega$)

Component	Receiver with Termination	Receiver without Termination	Unit
R _{1a} , R _{1b}	10,000	130	Ω
R_{2a}, R_{2b}	5600	64	Ω
C_{C}	0.1	0.1	μF
V _{CM}	1.2	1.2	V

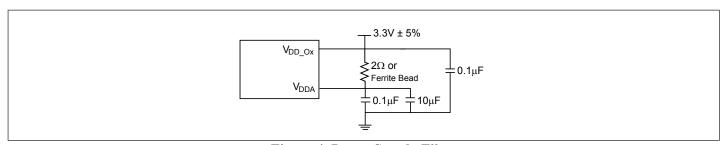


Figure 4. Power Supply Filter

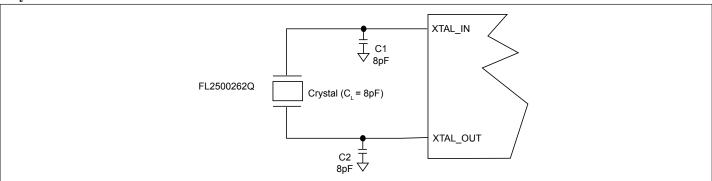




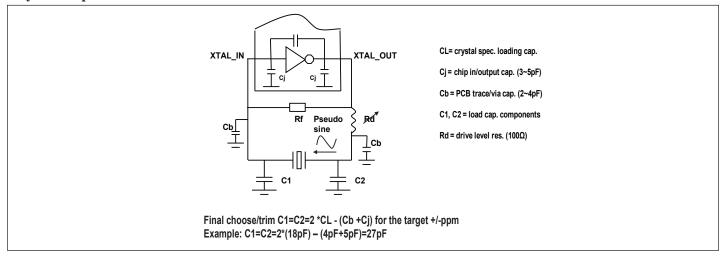
Crystal Circuit Connection

The following diagram shows PI6CG33402C crystal circuit connection with a parallel crystal. For the CL = 8pF crystal, it is suggested to use C1 = 8pF, C2 = 8pF. C1 and C2 can be adjusted to fine tune to the target ppm of crystal oscillator according to different board layouts based on the following formula in the Crystal Capacitor Calculation diagram.

Crystal Oscillator Circuit



Crystal Capacitor Calculation



Recommended Crystal Specification

Diodes Recommends:

- a) FL2500217, SMD 3.2x2.5(4P), 25MHz, CL=8pF, +/-20ppm, https://www.diodes.com/assets/Datasheets/FL.pdf
- b) FH2500016, SMD 2.5x2.0(4P), 25MHz, CL=8pF, +/-30ppm, https://www.diodes.com/assets/Datasheets/FH.pdf
- c) FW2500031, SMD 2.0x1.6(4P), 25MHz, CL=8pF, +/-30ppm, https://www.diodes.com/assets/Datasheets/FW.pdf
- d) US2500003, SMD 1.6x1.2(4P), 25MHz, CL=12pF, +/-30ppm, https://www.diodes.com/assets/Datasheets/US.pdf

Table 4. Thermal Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
θ_{JA}	Thermal Resistance Junction to Ambient	Still air			44.7	°C/W
θ_{JC}	Thermal Resistance Junction to Case				21.7	°C/W





Part Marking

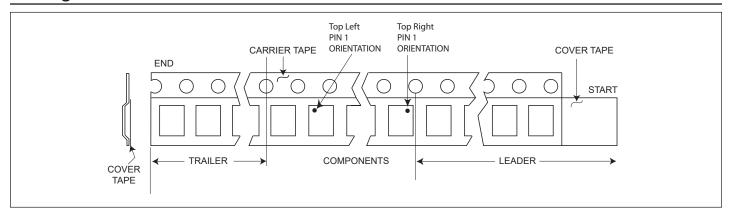
PI6CG33 402CZHIE YYWWXX

YY: Year

WW: Workweek

1st X: Assembly Code 2nd X: Fab Code

Package Information

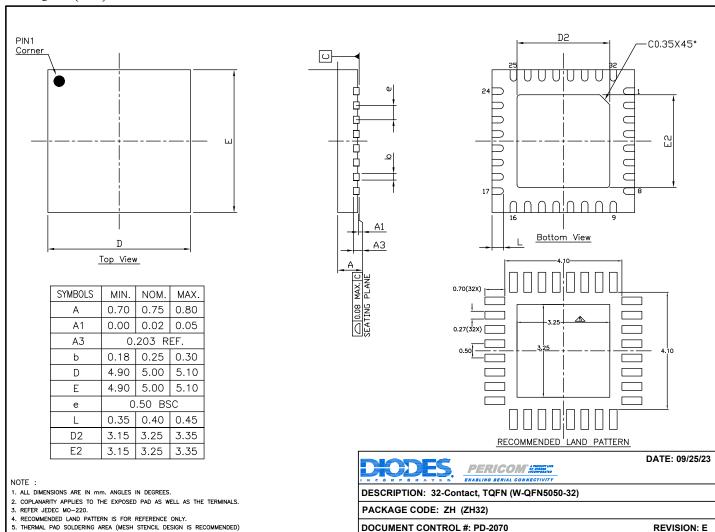






Packaging Mechanical

32-TQFN (ZH)



For latest package information:

 $See \ http://www.diodes.com/design/support/packaging/pericom-packaging/packaging-mechanicals-and-thermal-characteristics/.$

Ordering Information

Ordering Code	Package Code	Package Description	Pin 1 Location
PI6CG33402CZHIEX	ZH	32-Contact, Thin Quad Flat No-Lead (TQFN)	Top Right Corner
PI6CG33402CZHIEX-13R	ZH	32-Contact, Thin Quad Flat No-Lead (TQFN)	Top Left Corner

Notes:

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant.
- 2. See https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. E = Pb-free and Green
- 5. X suffix = Tape/Reel
- 6. For packaging details, go to our website at: https://www.diodes.com/assets/MediaList-Attachments/Diodes-Package-Information.pdf





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